10/788,730

First Named Inventor	Yonjun Jeff Hu
Serial No.	Unknown
Filing Date	Herewith 3/22/04
Group Art Unit	Unknown 525 3
Examiner Name	Unknown Col Single
Attorney Docket No.	400 08411502

## INFORMATION DISCLOSURE STATEMENT FORM PTO-1449

Title: AGGLOMERATION CONTROL USING EARLY TRANSITION METAL ALLOYS

U.S. Patent References				
Examiner Initials	Patent No.	Issue Date	Name	Filing Date
	4,441,964	04-10-1984	Mikkers et al.	01-21-1983
7	4,985,750	01-15-1991	Hoshino	09-17-1987
	5,118,661	06-02-1992	Maeda	11-20-1990
4	5,744,394	04-28-1998	Iguchi et al.	04-23-1997
	5,786,269	07-28-1998	Murakami et al.	09-02-1996
	5,391,517	02-21-1995	Gelatos et al.	09-13-1993
	5,980,977	11-09-1999	Deng et al.	12-09-1996
	5,990,011	11-23-1999	McTeer	09-18-1997
	.6,001,461	12-14-1999	Toyoda et al.	12-19-1996
	6,084,302	07-04-2000	Sandhu	12-26-1995
	6,126,989	10-03-2000	Robinson et al.	08-26-1998
	6,133,139	10-17-2000	Dalal et al.	10-08-1997
	6,165,555	12-26-2000	Jun et al.	07-21-1998
,	6,194,108B1	02-27-2001	Akutsu et al.	10-06-1997
	6,194,315B1	02-27-2001	Hu et al.	04-16-1999
	6,258,710B1	07-10-2001	Rathore et al.	12-10-1999

			Forei	gn Patent Refer	ences	AND THE PROPERTY OF THE PROPER	1997
Examiner	Foreign Pa	tent		Name		Publication Date	T?
Initials	Country	No.					<b>↓</b>
							<u> </u>

. 2	Other References					
Examiner Initials	Author, Title, Date, Pages, etc.					
6	De Boer et al., "Cohesion in Metals: Transition Metal Alloys", 1988, Amsterdam, North Holland-Elsevier Science, pp. preface-101, 105-142, 339-381, 495-535					
1	Subramanian et al., "Binary Alloy Phase Diagrams", 1990, Volume I, pp. 51-52, 88, 90,113-115, 1416, 1418-1419, 1428-1429, 1494-1496, 1473-1475, 1505-1506, 1511-1513					
	Wang et al., "Binary Cu-alloy layers for Cu-interconnections reliability improvement" IEEE International Proceedings on Interconnect Technology Conference, 4-6 June 2001, pp 86-88					
6	Nogami et al., "Characterization of the Cu/Barrier Metal Interface for Copper Interconnects", IEEE International Proceedings on Interconnect Technology Conference, 1-3 June 1998, pp 298-300					